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**Integrated circuits – EMC evaluation of transceivers –
Part 3: CAN transceivers**

**Circuits intégrés – Évaluation de la CEM des émetteurs-récepteurs –
Partie 3: Émetteurs-récepteurs CAN**



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IEC Central Office
3, rue de Varembe
CH-1211 Geneva 20
Switzerland

Tel.: +41 22 919 02 11
info@iec.ch
www.iec.ch

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CONTENTS

FOREWORD.....	6
1 Scope.....	8
2 Normative references	8
3 Terms, definitions and abbreviated terms	9
3.1 Terms and definitions.....	9
3.2 Abbreviated terms.....	10
4 General	10
5 Test and operating conditions.....	11
5.1 Supply and ambient conditions.....	11
5.2 Test operation modes	12
5.3 Test configuration	12
5.3.1 General test configuration for transceiver network	12
5.3.2 General test configuration for unpowered ESD test.....	13
5.3.3 Transceiver network tests – Coupling ports and networks	14
5.3.4 ESD tests – Coupling ports and networks	15
5.4 Test signals	16
5.4.1 General	16
5.4.2 Test signals for normal operation mode	16
5.4.3 Test signal for wake-up from low power mode	18
5.5 Evaluation criteria	22
5.5.1 General	22
5.5.2 Evaluation criteria for functional operation modes.....	22
5.5.3 Evaluation criteria in unpowered condition after exposure to disturbances	28
5.5.4 Status classes	29
6 Test and measurement.....	29
6.1 Emission of RF disturbances.....	29
6.1.1 Test method	29
6.1.2 Test setup	29
6.1.3 Test procedure and parameters	30
6.2 Immunity to RF disturbances.....	31
6.2.1 Test method	31
6.2.2 Test setup	31
6.2.3 Test procedure and parameters	32
6.3 Immunity to impulses	37
6.3.1 Test method	37
6.3.2 Test setup	37
6.3.3 Test procedure and parameters	38
6.4 Electrostatic discharge (ESD)	41
6.4.1 Test method	41
6.4.2 Test setup	41
6.4.3 Test procedure and parameters	43
7 Test report.....	44
Annex A (normative) CAN test circuits	45
A.1 General.....	45
A.2 Test circuit for CAN transceivers for functional tests	45

A.3	Test circuit for CAN transceiver for ESD test.....	49
Annex B (normative)	Test circuit boards.....	51
B.1	Test circuit board for functional tests	51
B.2	ESD test	51
Annex C (informative)	Examples for test limits for CAN transceiver in automotive application	53
C.1	General.....	53
C.2	Emission of RF disturbances.....	53
C.3	Immunity to RF disturbances.....	54
C.4	Immunity to impulses	57
C.5	Electrostatic discharge (ESD)	57
Annex D (informative)	Characterization of common mode choke for CAN bus interfaces.....	58
D.1	General.....	58
D.2	Abbreviations.....	58
D.3	CMC test.....	58
D.3.1	General	58
D.3.2	Leakage inductance mismatch measurement.....	59
D.3.3	S-parameter measurement mixed mode.....	63
D.3.4	ESD damage	68
D.3.5	Saturation test at RF disturbances.....	71
Bibliography.....		74
Figure 1 –	General test configuration for tests in transceiver network	13
Figure 2 –	General test configuration for unpowered ESD test	13
Figure 3 –	Transceiver network tests – coupling ports and networks	14
Figure 4 –	Coupling ports and networks for ESD tests	16
Figure 5 –	Definition for trigger point and violation masks for CAN transceivers with flexible data rate capability	26
Figure 6 –	Principal drawing of the maximum deviation on an I-V characteristic	28
Figure 7 –	Test setup for measurement of RF disturbances	30
Figure 8 –	Test setup for DPI tests.....	32
Figure 9 –	Test setup for impulse immunity tests	37
Figure 10 –	Test setup for direct ESD tests – principal arrangement.....	42
Figure 11 –	Test setup for direct ESD tests – stimulation and monitoring.....	43
Figure A.1 –	General drawing of the circuit diagram of test network for CAN standard transceivers for functional test.....	47
Figure A.2 –	General drawing of the circuit diagram of test network for CAN PN transceivers for functional test.....	49
Figure A.3 –	General drawing of the circuit diagram for direct ESD tests of CAN transceivers in unpowered mode.....	50
Figure B.1 –	Example of IC interconnections of CAN signal	51
Figure B.2 –	Example of ESD test board for CAN transceivers.....	52
Figure C.1 –	Example of limits for RF emission – CAN with bus filter	53
Figure C.2 –	Example of limits for RF emission – other global pins	54
Figure C.3 –	Example of limits for RF emission – local supplies.....	54

Figure C.4 – Example of limits for RF immunity for functional status class A _{IC} – CAN with bus filter	55
Figure C.5 – Example of limits for RF immunity for functional status class A _{IC} – CAN	55
Figure C.6 – Example of limits for RF immunity for functional status class A _{IC} – other global pins	56
Figure C.7 – Example of limits for RF immunity for functional status class C _{IC} or D _{IC} – CAN with bus filter	56
Figure C.8 – Example of limits for RF immunity for functional status class C _{IC} or D _{IC} – other global pins	57
Figure D.1 – General electrical drawing of a CMC	59
Figure D.2 – Test setup for 2-port S-Parameter measurements for leakage inductance evaluation	59
Figure D.3 – Example of a two-port test board for CMC leakage inductance characterization	60
Figure D.4 – Example of CMC characterization measurement results	63
Figure D.5 – Test setup for S-Parameter measurements	64
Figure D.6 – Example test board S-Parameter measurement – mixed mode, top layer	65
Figure D.7 – Example test board S-Parameter measurement – single ended, top layer	65
Figure D.8 – Recommended characteristics for S _{dd21} (IL)	67
Figure D.9 – Recommended characteristic for S _{cc21} (CMR)	68
Figure D.10 – Recommended characteristic for S _{sd21} and S _{sr12} (DCMR)	68
Figure D.11 – Test setup for ESD damage tests	69
Figure D.12 – Example test board ESD, top layer	70
Figure D.13 – Test setup for RF saturation measurements	71
Figure D.14 – Example RF saturation / S-Parameter test board, top layer	72
Table 1 – Overview of measurement and tests	11
Table 2 – Supply and ambient conditions for functional operation	12
Table 3 – Transceiver network tests – component value definitions of coupling ports and networks	15
Table 4 – Definitions of coupling ports for ESD tests	16
Table 5 – Communication test signal TX1	17
Table 6 – Communication test signal TX2a	17
Table 7 – Communication test signal TX2b	18
Table 8 – Wake-up test signal TX3	18
Table 9 – Communication test signal TX4a	19
Table 10 – Communication test signal TX4b	19
Table 11 – Communication test signal TX4c	19
Table 12 – Communication test signal TX4d	20
Table 13 – Communication test signal TX4e	20
Table 14 – Communication test signal TX4f1	20
Table 15 – Communication test signal TX4f2	21
Table 16 – Communication test signal TX4g	21
Table 17 – Communication test signal TX4h	21
Table 18 – Communication test signal TX4i	22

Table 19 – Evaluation criteria for CAN transceiver standard functions	23
Table 20 – Evaluation criteria for CAN transceivers with partial networking functionality	23
Table 21 – Specific definition for test procedure for evaluation of CAN transceiver partial networking function	24
Table 22 – Evaluation criteria for CAN transceivers with flexible data rate capability.....	25
Table 23 – Definitions for violation masks for CAN transceivers with flexible data rate capability	27
Table 24 – Definition of functional status classes	29
Table 25 – Settings of the RF measurement equipment	31
Table 26 – RF emission measurements	31
Table 27 – Specifications for DPI tests	33
Table 28 – DPI tests for functional status class A _{1C} evaluation of CAN transceiver standard function	34
Table 29 – DPI tests for functional status class A _{1C} evaluation of CAN transceiver partial networking function	35
Table 30 – DPI tests for functional status class A _{1C} evaluation of CAN transceiver CAN FD function	36
Table 31 – DPI tests for functional status class C _{1C} or D _{1C} evaluation of CAN transceivers	36
Table 32 – Specifications for impulse immunity tests	38
Table 33 – Parameters for impulse immunity test	38
Table 34 – Impulse immunity tests for functional status class A _{1C} evaluation of CAN transceiver standard function	39
Table 35 – Impulse immunity tests for functional status class A _{1C} evaluation of CAN transceiver partial networking function	40
Table 36 – Impulse immunity tests for functional status class A _{1C} evaluation of CAN transceiver CAN FD function	40
Table 37 – Impulse immunity tests for functional status class C _{1C} or D _{1C} evaluation of CAN transceivers	41
Table 38 – Specifications for direct ESD tests	43
Table 39 – ESD tests in unpowered mode for functional status class D _{1C} evaluation of CAN transceivers	44
Table B.1 – Parameters of ESD test circuit board	52
Table C.1 – Example of limits for impulse immunity for functional status class C _{1C} or D _{1C} ..	57
Table D.1 – Test procedure and parameters for leakage inductance evaluation	61
Table D.2 – Leakage inductance measurements	62
Table D.3 – Leakage inductance mismatch classes	63
Table D.4 – Test procedure and parameters for 3-port test board characterization	64
Table D.5 – Test procedure and parameters for S-Parameter measurements	66
Table D.6 – Required S-Parameter measurements	67
Table D.7 – Test parameters for ESD damage tests	70
Table D.8 – Required ESD tests for damage	71
Table D.9 – Test procedure and parameters for RF saturation tests	72
Table D.10 – Required RF saturation tests	73

INTERNATIONAL ELECTROTECHNICAL COMMISSION

**INTEGRATED CIRCUITS –
EMC EVALUATION OF TRANSCEIVERS –****Part 3: CAN transceivers**

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International Standard IEC 62228-3 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

This first edition cancels and replaces the first edition of IEC TS 62228 published in 2007 and constitutes a technical revision.

This edition includes the following significant technical changes with respect to IEC TS 62228:

- a) introduction of CAN transceivers with partial networking functionality and CAN transceivers with flexible data rate capability and addition of operation modes and test descriptions in the respective subclauses of the document;
- b) introduction of minimal communication network with two CAN transceivers;
- c) update of the test requirements and targets in Annex C;
- d) addition of Annex D for common mode choke characterization.

The text of this standard is based on the following documents:

CDV	Report on voting
47A/1050/CDV	47A/1069/RVC

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

A list of all parts in the IEC 62228 series, published under the general *title Integrated circuits – EMC evaluation of transceivers*, can be found on the IEC website.

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INTEGRATED CIRCUITS – EMC EVALUATION OF TRANSCEIVERS –

Part 3: CAN transceivers

1 Scope

This part of IEC 62228 specifies test and measurement methods for EMC evaluation of CAN transceiver ICs under network condition. It defines test configurations, test conditions, test signals, failure criteria, test procedures, test setups and test boards. It is applicable for CAN standard transceivers, CAN transceivers with partial networking functionality and CAN transceivers with flexible data rate capability and covers

- the emission of RF disturbances,
- the immunity against RF disturbances,
- the immunity against impulses, and
- the immunity against electrostatic discharges (ESD).

2 Normative references

The following documents are referred to in the text in such a way that some or all of their content constitutes requirements of this document. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

IEC 61967-1, *Integrated circuits – Measurement of electromagnetic emissions – Part 1: General conditions and definitions*

IEC 61967-4, *Integrated circuits – Measurement of electromagnetic emissions, 150 kHz to 1 GHz – Part 4: Measurement of conducted emissions – 1 Ω /150 Ω direct coupling method*

IEC 62132-1, *Integrated circuits – Measurement of electromagnetic immunity – Part 1: General conditions and definitions*

IEC 62132-4, *Integrated circuits – Measurement of electromagnetic immunity 150 kHz to 1 GHz – Part 4: Direct RF power injection method*

IEC 62215-3, *Integrated circuits – Measurement of impulse immunity – Part 3: Non-synchronous transient injection method*

IEC 62228-1, *Integrated circuits – EMC evaluation of transceivers – Part 1: General conditions and definitions*

ISO 7637-2, *Road vehicles – Electrical disturbances from conduction and coupling – Part 2: Electrical transient conduction along supply lines only*

ISO 10605, *Road vehicles – Test methods for electrical disturbances from electrostatic discharge*

ISO 11898-1, *Road vehicles – Controller area network (CAN) – Part 1: Data link layer and physical signalling*